



## Customer Information Notification

201711002I

**Issue Date:** 11-Nov-2017  
**Effective Date:** 12-Nov-2017

Here's your personalized quality information concerning products Digi-Key purchased from NXP. For detailed information we invite you to view this notification online



# QUALITY

### Change Category

- |  |   |  |   |   |
|--|---|--|---|---|
| <input type="checkbox"/> Wafer Fab Process   | <input type="checkbox"/> Assembly Process   | <input type="checkbox"/> Product Marking           | <input type="checkbox"/> Test Location  | <input checked="" type="checkbox"/> Design              |
| <input type="checkbox"/> Wafer Fab Materials | <input type="checkbox"/> Assembly Materials | <input type="checkbox"/> Mechanical Specification  | <input type="checkbox"/> Test Process   | <input type="checkbox"/> Errata                         |
| <input type="checkbox"/> Wafer Fab Location  | <input type="checkbox"/> Assembly Location  | <input type="checkbox"/> Packing/Shipping/Labeling | <input type="checkbox"/> Test Equipment | <input type="checkbox"/> Electrical spec./Test coverage |

**PWRSBC\_LIN Design  
Change for SCAN Mode  
Entry / Vpre**

### Information Notification

NXP Semiconductors announces a design change for the PWRSBC\_LIN devices associated with this notification. NXP has identified some very specific conditions that can lead to the PWRSBC\_LIN devices to unexpectedly enter SCAN (test) mode. A looping structure in the design has been identified and can trigger SCAN mode entry, preventing Vpre to start when Vsup input supply voltage is applied to the device. The behaviour is visible on applications with switched battery supply only during power-up phase. To improve design robustness, NXP has implemented a minor metal design modification for the PWRSBC\_LIN product family.

All the PWRSBC\_LIN product family is impacted: MC33907NAE/R2, MC33907LAE/R2, MC33908NAE/R2, MC33908LAE/R2.

Design modification described above will be applied on all the PWRSBC\_LIN product family: MC33907NAE/R2, MC33907LAE/R2, MC33908NAE/R2, MC33908LAE/R2

Corresponding ZVEI Delta Qualification Matrix ID: SEM-DE-02

Please see the attached files for additional details.

**Why do we issue this Information Notification**

PWRSBC\_LIN product design change is implemented to resolve unexpected SCAN mode entry, which prevents Vpre to start when Vsup input supply voltage is applied to the device.

**Identification of Affected Products**

Product identification will be tracked through date codes.

**Impact**

There is no product specification change, nor fit, form, function change.  
This change is provided as a running change, no customer impact expected.

**Disposition of Old Products**

Existing inventory will be shipped until depleted

**Contact and Support**

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

For specific questions on this notice or the products affected please contact our specialist directly:

**Name** Carmen Ortigosa  
**Position** Quality Engineer  
**e-mail address** carmen.ortigosa@nxp.com

At NXP Semiconductors we are constantly striving to improve our product and processes to ensure they reach the highest possible Quality Standards.

Customer Focus, Passion to Win.

NXP Quality Management Team.

**About NXP Semiconductors**

NXP Semiconductors N.V. (NASDAQ: NXPI) provides High Performance Mixed Signal and Standard Product solutions that leverage its leading RF, Analog, Power Management, Interface, Security and Digital Processing expertise. These innovations are used in a wide range of automotive, identification, wireless infrastructure, lighting, industrial, mobile, consumer and computing applications.

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NXP Semiconductors  
High Tech Campus, 5656 AG Eindhoven, The Netherlands

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Changed Orderable Part#	Changed Part 12NC	Changed Part Number	Changed Part Description	Package Name	Status	Product Line	Notes
MC33907NAE	935312441557	MC33907NAE	POWER SBC LIN	HLQFP48	RFS	BL Advanced Automotive Analog	MC33907NAE
MC33908LAE	935311339557	MC33908LAE	POWER SBC LIN	HLQFP48	RFS	BL Advanced Automotive Analog	MC33908LAE
MC33908NAE	935313228557	MC33908NAE	POWER SBC LIN	HLQFP48	RFS	BL Advanced Automotive Analog	MC33908NAE
MC33907LAE	935312346557	MC33907LAE	POWER SBC LIN	HLQFP48	RFS	BL Advanced Automotive Analog	MC33907LAE